

MC68030 ELECTRICAL SPECIFICATIONS



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ELECTRICAL SPECIFICATIONS

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Supply Voltage*	v _{CC}	-0.3 to +7.0	V
Input Voltage	v _{in}	- 0:5 to + 7.0	V
Operating Temperature Range Minimum Ambient Temperature 40-MHz Maximum Ambient Temperature 50-MHz Maximum Case Temperature	TA TA	0 70 80	۳С
Storage Temperature Range	T _{stg}	-55 to 150	°C

static voltages or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either GND or V_{CC}).

This device contains protective circuitry against damage due to high

THERMAL CHARACTERISTICS — PGA PACKAGE

Characteristic	Symbol	Value	Rating
Thermal Resistance — Ceramic			°C/W
Junction to Ambient	₀ JA -	30*	
Junction to Case	⊕JC	15*	ľ

^{*}Estimated

^{*}A continuous clock must be supplied to the MC68030 when it is powered

POWER CONSIDERATIONS

The average chip-junction temperature, T_J, in °C can be obtained from:

$$T_{J} = T_{A} + (P_{D} \cdot \theta_{JA}) \tag{1}$$

where:

T_A = Ambient Temperature, °C θ_J_A = Package Thermal Resistance, Junction-to-Ambient, °C/W

PD = PINT + PI/O

 P_{INT} = $I_{CC} \times V_{CC}$, Watts — Chip Internal Power $P_{I/O}$ = Power Dissipation on Input and Output Pins

- User Determined

For most applications P_{I/O}<P_{INT} and can be neglected.

The following is an approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected):

$$P_D = K \div (T_J + 273^{\circ}C)$$
 (2)

Solving equations (1) and (2) for K gives:

$$K = P_D \cdot (T_A + 273^{\circ}C) + \theta_{JA} \cdot P_D^2$$
 (3)

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring PD (at equilibrium) for a known TA. Using this value of K, the values of PD and TJ can be obtained by solving equations (1) and (2) iteratively for any value of TA.

The total thermal resistance of a package (θ_{JA}) can be separated into two components, θ_{JC} and θ_{CA} , representing the barrier to heat flow from the semiconductor junction to the package (case) surface (θ_{JC}) and from the case to the outside ambient (θ_{CA}) . These terms are related by the equation:

$$\theta J A = \theta J C + \theta C A \tag{4}$$

 θ JC is device related and cannot be influenced by the user. However, θ CA is user dependent and can be minimized by such thermal management techniques as heat sinks, ambient air cooling, and thermal convection. Thus, good thermal management on the part of the user can significantly reduce θ CA so that θ JA approximately equals θ JC. Substitution of θ JC for θ JA in equation (1) will result in a lower semiconductor junction temperature.

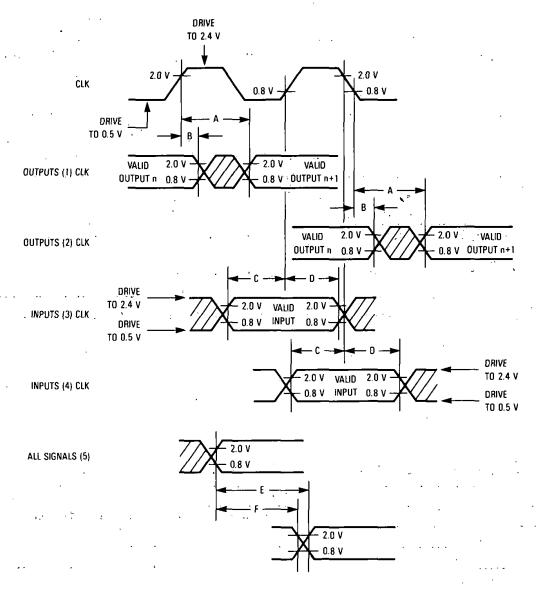
Values for thermal resistance presented in this document, unless estimated, were derived using the procedure described in Motorola Reliability Report 7843, "Thermal Resistance Measurement Method for MC68XX Microcomponent Devices," and are provided for design purposes only. Thermal measurements are complex and dependent on procedure and setup. User derived values for thermal resistance may differ.

AC ELECTRICAL SPECIFICATIONS DEFINITIONS

The AC specifications presented consist of output delays, input setup and hold times, and signal skew times. All signals are specified relative to an appropriate edge of the MC68030 clock input and, possibly, relative to one or more other signals.

The measurement of the AC specifications is defined by the waveforms in Figure 1. To test the parameters guaranteed by Motorola, inputs must be driven to the voltage levels specified in Figure 1. Outputs of the MC68030 are specified with minimum and/or maximum limits, as appropriate, and are measured as shown. Inputs to the MC68030 are specified with minimum and, as appropriate, maximum setup and hold times, and are measured as shown. Finally, the measurements for signal-to-signal specifications are also shown.

Note that the testing levels used to verify conformance of the MC68030 to the AC specifications does not affect the guaranteed DC operation of the device as specified in the DC electrical characteristics.



NOTES:

- 1 This output timing is applicable to all parameters specified relative to the rising edge of the clock
- 2 This output timing is applicable to all parameters specified relative to the falling edge of the clock
- 3 This input timing is applicable to all parameters specified relative to the rising edge of the clock
- 4 This input timing is applicable to all parameters specified relative to the falling edge of the clock
- 5 This timing is applicable to all parameters specified relative to the assertion/negation of another signal

LEGEND:

- A Maximum output delay specification
- B Minimum output hold time
- C Minimum input setup time specification
- D Minimum input hold time specification
- E Signal valid to signal valid specification (maximum or minimum)
- F Signal valid to signal invalid specification (maximum or minimum)

Figure 1. Drive Levels and Test Points for AC Specifications

DC ELECTRICAL SPECIFICATIONS

 $(V_{CC} = 5.0 \text{ Vdc} \pm 5\%; \text{ GND} = 0 \text{ Vdc}; 40 \text{ MHz-T}_{A} = 0^{\circ} \text{ to } 70^{\circ}\text{C}, 50 \text{ MHz-T}_{A} = 0^{\circ}\text{C to } T_{C} = 80^{\circ}\text{C})$

<u>Characteristic</u>	Symbol	Min	Max	Unit
Input High Voltage	V _{IH}	2.0	v _{cc}	V.
Input Low Voltage	V _{IL}	GND 0.5	0.8	٧
Input Leakage Current \overline{BERR} , \overline{BR} , \overline{BGACK} , CLK , \overline{IPLO} - $\overline{IPL2}$, \overline{ACO} \overline{CDIS} , \overline{DSACKO} , \overline{DSA}	ACK1	- 2.5	2.5	μА
HALT, RI	ESET	- 20	20	
· Hi-Z (Off-State) Leakage Current A0-A31, AS, DBEN, DS, D0-D31, FC0- ω 2.4 V/0.5 V R/W, RMC, SIZ0-		- 20	20	μА
Output High Voltage A0-A31, \overline{AS} , \overline{BG} , D0-D31, \overline{DBEN} , \overline{DS} , \overline{ECS} , R/W, \overline{IP} OCS, \overline{RMC} , SIZ0-SIZ1, FC0-CBREQ, CIOUT, STATUS, \overline{RI}	-FC2,	2.4	-	٧.
Output Low Voltage $ \begin{array}{ccccccccccccccccccccccccccccccccccc$	END		0.5 0.5 0.5 0.5	٧ .
Power Dissipation (T _A = 0°C)	P _D .	_	2.6	w
Capacitance (see Note) $V_{in} = 0 \text{ V}, T_A = 25^{\circ}\text{C}, f = 1 \text{ MHz}$	C _{in}		20	pF
Load Capacitance ECS, CIOUT, STATUS, RE		_	50 70 130	pF

NOTE: Capacitance is periodically sampled rather than 100% tested.

AC ELECTRICAL SPECIFICATIONS — CLOCK INPUT (see Figure 2)

Num.	Characteristic	20	MHz	25 İ	ViHz	·33.33	MHz	40 1	VIHz	50 MHz*]
iaum.		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
	Frequency of Operation	12.5	· 20	12.5	25	20	33.33	25	40	25	50	MHz
1	Cycle Time Clock	50	-80	40	80	30	50	25	40	20	40	ns
2, 3	Clock Pulse Width Measured from 1.5 V to 1.5 V	23	57	19	- 61	14	36	11.5	29	9.5	30.5	ns
4, 5	Clock Rise and Fall Times	_	5	_	4	_	3.	_	2	_	2	ns

^{*}T_{case} = 80°C Maximum . . .

AC ELECTRICAL SPECIFICATIONS — READ AND WRITE CYCLES (V_{CC} = 5.0 Vdc ±5%; GND = 0 Vdc; 40 MHz-T_A = 0° to 70°C, 50 MHz-T_A = 0°C to T_C = 80°C) (see. Figures .3-8)

N		20 (VIHZ	25 1	VIHz	33.33	MHz	40 (VIHz	50 N	1Hz*	
Num.	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
6	Clock High to Function Code, Size, RMC, IPEND, CIOUT, Address Valid	. 0	25	0	20	0	14	0	14	0	14	ns
6A	Clock High to ECS, OCS Asserted	0	15	0	15	0	12	0	10	0	10	ns
6B ,	Function Code, Size, RMC, IPEND, CIOUT, Address Valid to Negating Edge of ECS	4	1	3		3	_ `	3		3	1.	ns
. 7	Clock High to Function Code, Size, RMC, CIOUT, Address, Data High Impedance	0	50	0	40	0	30	0	25	0	20	ns
.8	Clock High to Function Code, Size, RMC, IPEND, CIOUT, Address Invalid	0		0	1	0		0		0	ĺ.	ns
9	Clock Low to AS, DS Asserted, CBREQ Valid	3	20	3	18	2	10	2	10 .	2	10	ns
9A ¹	AS to DS Assertion Skew (Read)	- 10	10	- 10	10	-8	8	- 6	6	-6	6	ns
9B ¹⁴	AS Asserted to DS Asserted (Write)	32	1	27	1	22	_	16	_	14	İ	ns
10	ECS Width Asserted	15		10	. —	-8		5		4	_	ns
10A	OCS Width Asserted	15		10		8	· —	5		4		ns
10B ⁷	ECS, OCS Width Negated	10	_	5		5		· 5	_	4		ns
	Function Code, Size, RMC, CIOUT, Address Valid to Asserting Edge of AS Asserted (and DS Asserted, Read)	10	_	7		·5·		5	 	3		ns
12	Clock Low to AS, DS, CBREQ Negated	0	20	0	18	0	10	0	10	0	10 [°]	ns
12A	Clock Low to ECS/OCS Negated	0	20	0 .	18	0	15	~ o ·	12	0	11	ns
13	AS, DS Negated to Function Code, Size, RMC, CIOUT, Address Invalid	10		7		5	:	3		3	_	ns
.14	AS (and DS Read) Width Asserted (Asynchronous Cycle)	85	_	70	_	45	_	30	_	25	_	ns
14A ¹¹	DS Width Asserted (Write)	38	· <u>·</u>	30	_	23	_	18		⁻ 13		. ns
14B	AS (and DS, Read) Width Asserted (Synchronous Cycle)	35	_	30	_	23	· <u> </u>	18	-	13	_	ns
.15	AS, DS Width Negated	38		30		23		18		. 13		·ns
15A ⁸	DS Negated to AS Asserted	30.	. — .	25		18		16 .	<u> </u>	14		ns
16	Clock High to AS, DS, R/W, DBEN, CBREQ High Impedance		50	-	40	_	30	_ _ _	25	_	20	ns

AC ELECTRICAL SPECIFICATIONS (Continued)

	0	20 1	VIHz	25 1	ИНz	33.33	MHz	40 [ŅНz	50 N	1Hz*	
Num.	Characteristic	Min	Мах	Min	Max	Min	Max	Min	Max	Min	Max	Unit
17	AS, DS Negated to R/W Invalid	10:	 ,	7.	:	5		3	_	3		ns
18	Clock High to R/W High	0	25	0	20	. 0	15	0	14	0	14	ns
20	Clock High to R/W Low	0	25	0	20	0	15	0.	14	0	14	ns
21	R/W High to AS Asserted	10 ·		`7 '	-	5	1	5	_	3	_	ns
22	R/W Low to DS Asserted (Write)	60		47		35	1	24		23	_	·ns
23	Clock High to Data-Out Valid	_	25	· —	20		14		14		14	nś
24	Data-Out Valid to Negating Edge of AS	8		5 .	_	3	-	3 .	_	3	1	ns
25 ¹¹	AS, DS Negated to Data-Out Invalid	10	_	7	·	5	,	3	-	. 3	-	ns
25A ^{9,11}	DS Negated to DBEN Negated (Write)	10		7	_	5		3	_	3		ns
26 ¹¹	Data-Out Valid to Asserting Edge of DS Asserted (Write)	10		7	-	5		3		3,	-	ns
27	Data-In Valid to Clock Low (Setup)	4	_	2	_	1	_	1'		1	_	ns
27A	Late BERR/HALT Asserted to Clock Low (Setup)	10	_	5	_	3	_	3	.— .	3.	-	ns
2812	AS, DS Negated to DSACKx, BERR, HALT, AVEC Negated (Asynchronous Hold)	0	50	0	40	0	. 30	0	20	0	15	ns
28A12	Clock Low to DSACKx, BERR, HALT, AVEC Negated (Synchronous Hold)	12	85	8	70	6	50	6	40	6	35	ns
29 ¹²	AS, DS Negated to Data-In Invalid (Asynchronous Hold)	0	_	0		0		0		0	_	ns
29A ¹²	AS, DS Negated to Data-In High Impedance	_	50	_	40	_	30	_	25	_	20	ns
3012	Clock Low to Data-In Invalid (Synchronous Hold)	12	_	. 8	_	6	_	6	_	6	<u> </u>	ns
30A ¹²	Clock Low to Data-In High Impedance (Read followed by Write)	_	75		60	_	45		30		25	ns
31 ² .	DSACKx Asserted to Data-In Valid (Asynchronous Data Setup)	_	43		28	_	20		14	_	13	ns
31A ³	DSACKx Asserted to DSACKx Valid (Skew)	_	10	_	7	_	5			_	3	ns
32	RESET Input Transition Time	— .	1.5		1.5	_	1.5 .	<u> </u>	1.5	· —	1.5	Clks
33	Clock Low to BG Asserted	0	25	0	20	0	15	0.	14	0	14	ns
34	Clock Low to BG Negated	0	25	0	20	0	15	0	14	.0	14	ns
35	BR Asserted to BG Asserted (RMC Not Asserted)	1.5	3.5	1.5	3.5	1.5	3.5	1.5	3.5	1.5	3.5	Clks

AC ELECTRICAL SPECIFICATIONS (Continued)

		20 1	ИНż	25	VIHz	33:33	MHz	40 1	VIHz	50 N	/iHz*	<u> </u>
Num.	Characteristic	Min	Max	' Min	Max	·Min	Max	Min	Max	Min	Max	Unit
37	BGACK Asserted to BG Negated	1.5	3.5	1.5	3.5	1.5	3.5	1.5	3.5	1.5	3.5	Clks
37A ⁶	BGACK Asserted to BR Negated	٠٥٠	1.5	0 [,]	1.5	0	1.5	0	1.5	0	1.5	Clks
39	BG Width Negated	75	1	60	_	45		30	_	30		ns
39A	BG Width Asserted	75		60		45	·	30		30		ns
40	Clock High to DBEN Asserted (Read)	0	25	[‡] 0	20	0	18	0	16	0	14	nş
41	Clock Low to DBEN Negated (Read)	0	25	0	20	0	18	0	16	0	14	ns
42	Clock Low to DBEN Asserted (Write)	0	25	0	20	0	18	0	16	0	14	ns
43 '	Clock High to DBEN Negated (Write)	0	25	0	20	0	18	0	16	0	14	ns
44	R/W Low to DBEN Asserted (Write)	10		7	_	5	_	5	_	5	_	ns
45 ⁵	DBEN Width Asserted Asynchronous Read Asynchronous Write	50 100	<u>-</u> -	40 80	_	30 60	_	22 45	<u> </u>	20 40	- -	nş
45A ⁹	DBEN Width Asserted Synchronous Read Synchronous Write	10 50	_	5 40		5 30	_	5 22		5 20		ns
46	R/W Width Asserted (Asynchronous Write or Read)	125	_	100	ŀ	75	-	50		40	<u> </u>	ns
46A	R/W Width Asserted (Synchronous Write or Read)	`75	<u> </u>	60	· —	45	-	30	· —	25	-	ns
47A	Asynchronous Input Setup Time to Clock Low	4	_	2	-	2	_	2		2	_	ns
478	Asynchronous Input Hold Time from Clock Low	12		8	· <u>-</u>	6	-	6	<u> </u>	6	_	ns
484	DSACKx Asserted to BERR, HALT Asserted	. –	20		25	1	18	<u> </u>	14	1	13	ns
53	Data-Out Hold from Clock High	3	_	3,	-	2		2	-	2	-	ns
55	R/W Asserted to Data Bus Impedance Change	25	_	20		15	-	11	-	11	_	ns
56	RESET Pulse Width (Reset Instruction)	512	_	512	_	512	1	512	1	512	-	Clks
57	BERR Negated to HALT Negated (Rerun)	0		0	_	0	_	0	_	0	_	ns
58 ¹⁰	BGACK Negated to Bus Driven	1	_	. 1	-	1		1	_	1	_	Clks
5910	BG Negated to Bus Driven	1		1	_	1		1		1	_	Clks

AC ELECTRICAL SPECIFICATIONS (Concluded)

Num.	Characteristic	20	MHz	25 1	VIHz	33.33	MHz	40 (VIHz	50 MHz*		11
Nulli.	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
60 ¹³	Synchronous Input Valid to Clock High (Setup Time)	4		2	-	2	_	2	_	2		ns
61 ¹³	Clock High to Synchronous Input Invalid (Hold Time)	12	_	8	_	6	_	6	_	6	_	ns
62	Clock Low to STATUS, REFILL Asserted	0	25	0	20	0	15	0	15	0	15	ns
63	Clock Low to STATUS, REFILL Negated	0	25	0	20	0	15	0	15	0	15	ns

NOTES:

- 1. This number can be reduced to 5 ns if strobes have equal loads.
- 2. If the asynchronous setup time (#47A) requirements are satisfied, the DSACKx low to data setup time (#31) and DSACKx low to BERR low setup time (#48) can be ignored. The data must only satisfy the data-in clock low setup time (#27) for the following clock cycle, and BERR must only satisfy the late BERR low to clock low setup time (#27A) for the following clock cycle.
- 3. This parameter specifies the maximum allowable skew between DSACK0 to DSACK1 asserted or DSACK1 to DSACK0 asserted; specification #47A must be met by DSACK0 or DSACK1.
- 4. This specification applies to the first (DSACKX) or DSACKX) DSACKX signal asserted. In the absence of DSACKX, BERR is an asynchronous input using the asynchronous input setup time (#47A).
- 5. DBEN may stay asserted on consecutive write cycles.
- 6. The minimum values must be met to guarantee proper operation. If this maximum value is exceeded, \overline{BG} may be reasserted.
- 7. This specification indicates the minimum high time for ECS and OCS in the event of an internal cache hit followed immediately by another cache hit, a cache miss, or an operand cycle.
- 8. This specification guarantees operation with the MC68881/MC68882, which specifies a minimum time for \overline{DS} negated to \overline{AS} asserted (specification #13A in the MC68881/MC68882 User's Manual). Without this specification, incorrect interpretation of specifications #9A and #15 would indicate that the MC68030 does not meet the MC68881/MC68882 requirements.
- This specification allows a system designer to guarantee data hold times on the output side of data buffers that have output enable signals generated with DBEN. The timing on DBEN precludes its use for synchronous READ cycles with no wait states.
- 10. These specifications allow system designers to guarantee that an alternate bus master has stopped driving the bus when the MC68030 regains control of the bus after an arbitration sequence.
- .11. DS will not be asserted for synchronous write cycles with no wait states.
- 12. These hold times are specified with respect to strobes (asynchronous) and with respect to the clock (synchronous). The designer is free to use either time.
- 13. Synchronous inputs must meet specifications #60 and #61 with stable logic levels for **all** rising edges of the clock while AS is asserted. These values are specified relative to the high level of the rising clock edge. The values originally published were specified relative to the low level of the rising clock edge.
- 14. This specification allows system designers to qualify the \overline{CS} signal of an MC68881/MC68882 with \overline{AS} (allowing 7 ns for a gate delay) and still meet the \overline{CS} to \overline{DS} setup time requirement (spec 8B) of the MC68881/MC68882.

^{*}T_{case} = 80°C Maximum

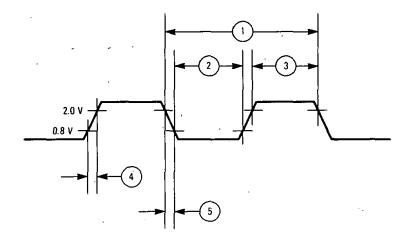


Figure 2. Clock Input Timing Diagram

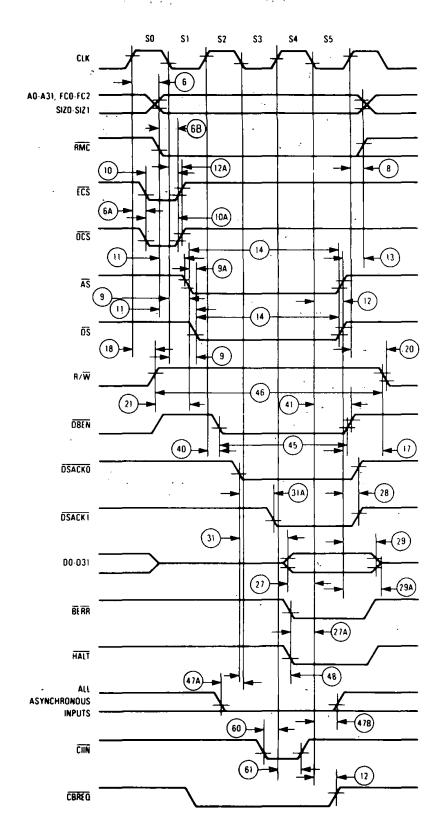


Figure 3. Asynchronous Read Cycle Timing Diagram

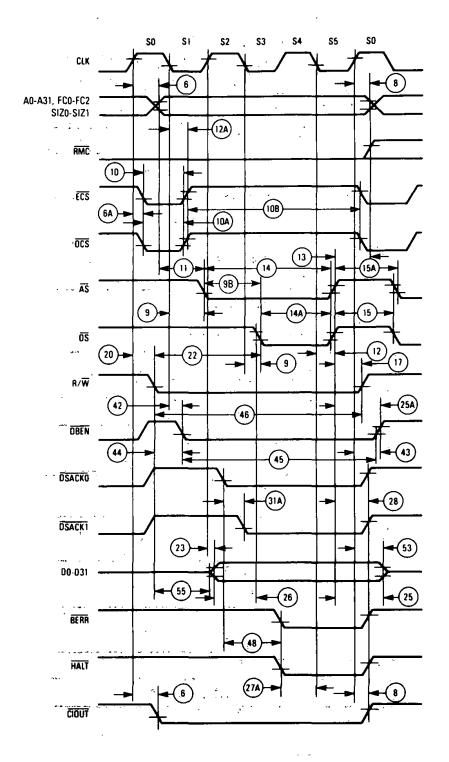


Figure 4. Asynchronous Write Cycle Timing Diagram

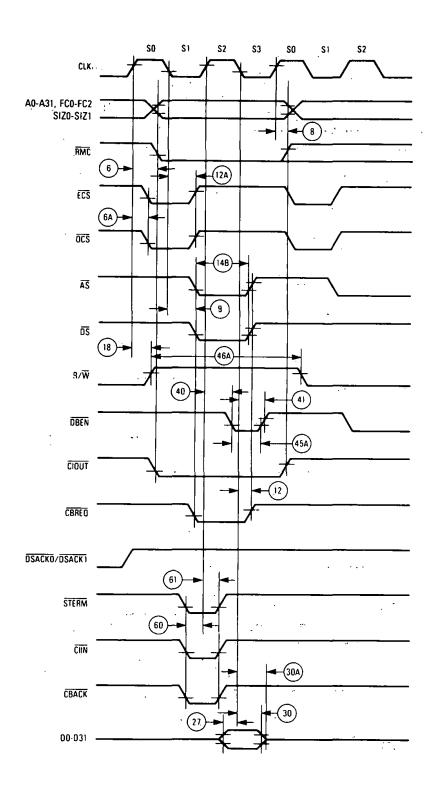


Figure 5. Synchronous Read Cycle Timing Diagram

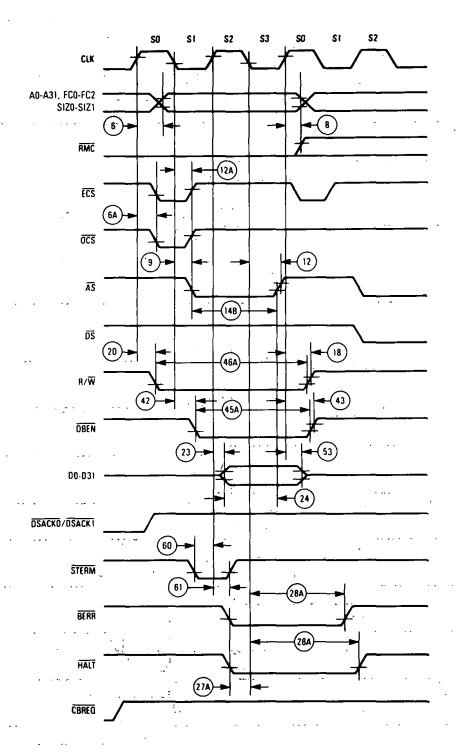


Figure 6. Synchronous Write Cycle Timing Diagram

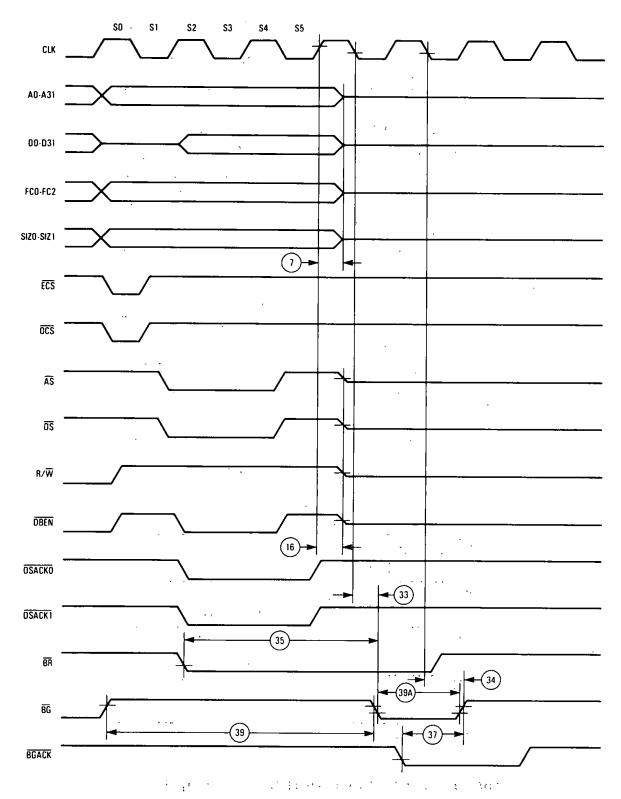


Figure 7. Bus Arbitration Timing Diagram

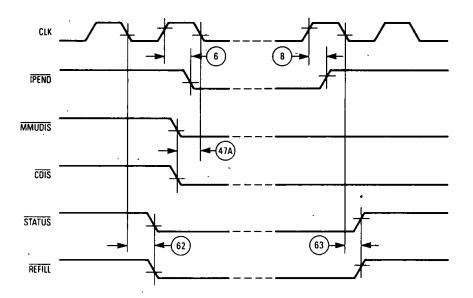


Figure 8. Other Signal Timings

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